

Spin-dependent transport and current modulation in a current-in-plane spin-valve field-effect transistor

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A spin metal-oxide semiconductor field-effect transistor (spin MOSFET), in which the source and drain electrodes are composed of ferromagnetic materials, has been intensively studied, aiming at future electronics applications [1,2]. Some experimental demonstrations of lateral and vertical spin MOSFETs have been reported thus far [3-6]; however, for both lateral and vertical spin MOSFETs, there still remain problems to overcome towards practical applications in the present status.

Here, we propose an alternative device, a current-in-plane spin-valve field-effect transistor (CIP-SV-FET), which comprises a ferromagnet / nonmagnet / ferromagnet trilayer and a gate electrode as shown in Fig. 1(a). This device can offer a functionality similar to that of spin MOSFETs due to the spin-valve effect and current modulation using a gate electric field. Also, the device performance is not affected by spin relaxation in the channel transport, which is a crucial issue in spin MOSFETs.

We fabricated a ferromagnetic-semiconductor GaMnAs-based CIP-SV-FET. The trilayer structure was grown on a lattice-relaxed $\text{In}_{0.17}\text{Al}_{0.83}\text{As}$ buffer layer [Fig. 1(b)], and thus the magnetic easy axes of the GaMnAs layers are perpendicular to the film plane. We measured the Hall resistance (R_{Hall}) and sheet resistance (R_{sheet}) under an external magnetic field $\mu_0 H$ applied perpendicular to the film plane. As shown in Figs. 1(c) and 1(d), R_{sheet} was modulated both by the magnetization configuration through the spin-valve effect (0.17%) and by the gate voltage (14%) at 36 K. Furthermore, we successfully demonstrated electric-field-assisted magnetization reversal of the upper GaMnAs layer [7].

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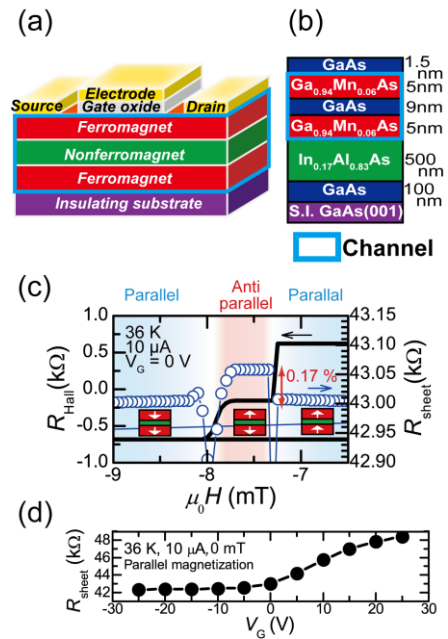


FIG. 1. (a)(b) Schematics of the current-in-plane spin-valve field-effect transistor (CIP-SV-FET) (a) and the heterostructure used in this study (b). (c) R_{Hall} (solid curve, left axis) and R_{sheet} (circles, right axis) vs. $\mu_0 H$. The gate voltage V_G is 0 V. (d) R_{sheet} vs. V_G . All data were taken with a bias current of 10 μA at 36 K.